



Product Change Notification: DSNO-08KARI721

Date:

14-Jun-2026

Product Category:

Switching Regulators

Notification Subject:

CCB 8080 Final Notice: Qualification of palladium coated copper with gold flash (CuPdAu) as a new bond wire material for MCP16301H-450E/CH, MCP16301HT-450E/CH, MCP16301HT-E/CH, MCP16301T-E/CH, MCP16301T-E/CHY, MCP16301T-I/CHY and MCP16331T-E/CH catalog part numbers (CPN) available in 6L SOT-23 package at MTAI assembly site.

Affected CPNs:

[DSNO-08KARI721_Affected_CPN_06142026.pdf](#)

[DSNO-08KARI721_Affected_CPN_06142026.csv](#)

PCN Status: Final Notification

PCN Type: Manufacturing Change

Microchip Parts Affected: Please open one of the files found in the Affected CPNs section.

Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change: Qualification of palladium coated copper with gold flash (CuPdAu) as a new bond wire material for MCP16301H-450E/CH, MCP16301HT-450E/CH, MCP16301HT-E/CH, MCP16301T-E/CH, MCP16301T-E/CHY, MCP16301T-I/CHY and MCP16331T-E/CH catalog part numbers (CPN) available in 6L SOT-23 package at MTAI assembly site.

Pre and Post Summary Changes:

	Pre Change	Post Change	Change (Yes/No)
Assembly Site	Microchip Technology Thailand (MTAI)	Microchip Technology Thailand (MTAI)	No

Wire Material	Au	CuPdAu	Yes
Die Attach Material	8006NS (PFAS-free)	8006NS (PFAS-free)	No
Molding Compound Material	G600V	G600V	No
Lead-Frame Material	C194	C194	No

Impacts to Datasheet: None

Change Impact: None

Reason for Change: To improve manufacturability by qualifying palladium coated copper with gold flash (CuPdAu) as a new bond wire material.

Change Implementation Status: In Progress

Estimated First Ship Date: 11 September 2026 (date code: 2637)

Note Below EFSD: Note: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

Timetable Summary:

	June 2026					>	September 2026				
Work Week	23	24	25	26	27		36	37	38	39	40
Qual Report Availability		x									
Final PCN Issue Date		x									
Estimated Implementation Date								x			

Method to Identify Change: Traceability Code

Qualification Report: Please open the attachments included with this PCN labeled as PCN_#_Qual_Report.

Revision History: June 14, 2026: Issued final notification.

Note: The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable product.

Attachments:

[PCN_DSNO-08KARI721_Qualification Report.pdf](#)

Please contact your local [Microchip sales office](#) with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to receive Microchip PCNs via email please register for our PCN email service at our [PCN home page](#) select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the [PCN FAQ](#) section.

If you wish to change your PCN profile, including opt out, please go to the [PCN home page](#) select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

Affected Catalog Part Numbers (CPN):

MCP16301H-450E/CH

MCP16301HT-450E/CH

MCP16301HT-E/CH

MCP16301T-E/CH

MCP16301T-E/CHY

MCP16301T-I/CHY

MCP16331T-E/CH



QUALIFICATION REPORT SUMMARY

RELIABILITY LABORATORY

PCN #: DSNO-08KARI721

Date:
June 09, 2026

Qualification of palladium coated copper with gold flash (CuPdAu) as a new bond wire material for MCP603T-E/CH, MCP603T-I/CH, MCP6043T-E/CH, MCP6043T-I/CH, MCP6143T-E/CH, MCP6273T-E/CH, MCP6283T-E/CH and MCP6293T-E/CH catalog part numbers (CPN) available in 6L SOT-23 package at MTAI assembly site. The MCP16301H-450E/CH, MCP16301HT-450E/CH, MCP16301HT-E/CH, MCP16301T-E/CH, MCP16301T-E/CHY, MCP16301T-I/CHY and MCP16331T-E/CH catalog part numbers (CPN) available in 6L SOT-23 package at MTAI assembly site will qualify by similarity (QBS).



MICROCHIP

PACKAGE QUALIFICATION REPORT

Purpose	Qualification of palladium coated copper with gold flash (CuPdAu) as a new bond wire material for MCP603T-E/CH, MCP603T-I/CH, MCP6043T-E/CH, MCP6043T-I/CH, MCP6143T-E/CH, MCP6273T-E/CH, MCP6283T-E/CH and MCP6293T-E/CH catalog part numbers (CPN) available in 6L SOT-23 package at MTAI assembly site. The MCP16301H-450E/CH, MCP16301HT-450E/CH, MCP16301HT-E/CH, MCP16301T-E/CH, MCP16301T-E/CHY, MCP16301T-I/CHY and MCP16331T-E/CH catalog part numbers (CPN) available in 6L SOT-23 package at MTAI assembly site will qualify by similarity (QBS).
CN	E000255869
QUAL ID	R2500021 Rev. A
MP CODE	A7BZ4YC8XF00
Part No.	MCP6293T-E/CH
Bonding No.	BD-002758 Rev. 01
CCB No.	7292 (Qual Date: February 28, 2025) and 8080
<u>Package</u>	
Type	6L SOT-23
<u>Lead Frame</u>	
Paddle size	72 x 41 mils
Material	A194
Surface	Ag single ring Plated
Process	Stamped
Lead Lock	No
Part Number	10100607
Treatment	BOT
<u>Material</u>	
Epoxy	84-3J/8006NS
Wire	CuPdAu wire
Mold Compound	G600V
Plating Composition	Matte Sn



MICROCHIP

PACKAGE QUALIFICATION REPORT

Manufacturing Information

Assembly Lot No.	Wafer Lot No.	Date Code
MTAI253800952.000	TMPE223515732.143	24513US
MTAI253900664.000	TMPE223515732.143	24524CA
MTAI253900665.000	TMPE223515732.143	24524CP

Result

☒ Pass ☐ Fail ☐ _____

6L SOT-23 assembled by MTAI pass reliability test per QCI-39000. This package was qualified the Moisture/Reflow Sensitivity Classification Level 1 at 260°C reflow temperature per IPC/JEDEC J-STD-020E standard.

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
<u>Precondition</u> <u>Prior Perform</u> <u>Reliability Tests</u> (At MSL Level 1)	Electrical Test: +25°C and 125°C System: ETS300 Bake 150°C, 24 hrs. System: CHINEE 85°C/85%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH 3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243	JESD22-A113 JIP/ IPC/JEDEC J-STD-020E	693(0)	0/693	Pass	Good Devices
	Electrical Test: +25°C and 125°C System: ETS300		693(0)	0/693	Pass	

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
Temp Cycle	Stress Condition: -65°C to +150°C, 500 Cycles System: TABAI ESPEC TSA-70H Electrical Test: +125°C System: ETS300 Bond Strength: Wire Pull (>2.50 grams)	JESD22-A104		231		Parts had been pre-conditioned at 260°C 77 units / lot
			231(0)	0/231	Pass	
			15(0)	0/15	Pass	
			15(0)	0/15	Pass	
UNBIASED-HAST	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X Electrical Test: +25°C System: ETS300	JESD22-A118		231		Parts had been pre-conditioned at 260°C 77 units / lot
			231(0)	0/231	Pass	
HAST	Stress Condition: +130°C/85%RH, 96 hrs. Bias Volt: 5.5 Volts System: HAST 6000X Electrical Test: +25°C and 125°C System: ETS300	JESD22-A110		231		Parts had been pre-conditioned at 260°C 77 units / lot
			231(0)	0/231	Pass	

PACKAGE QUALIFICATION REPORT						
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
High Temperature Storage Life	Stress Condition: Bake 175°C, 504 hrs. System: TPS Bake Oven	JESD22- A103		135		45 units / lot
	Electrical Test: +25°C and 125°C System: ETS300		135(0)	0/135	Pass	
Bond Strength Data Assembly	Wire Pull (>2.50 grams)	Mil. Std. 883-2011	30(0) Wires	0/30	Pass	
	Bond Shear (>15.00 grams)	CDF-AEC- Q100-001	30(0) Bonds	0/30	Pass	



QUALIFICATION REPORT SUMMARY

RELIABILITY LABORATORY

PCN #: DSNO-08KARI721

Date:
June 09, 2026

Qualification of an additional mold compound G600V for the 6L SOT-23 COL package with PPF lead-frame at MTAI assembly site. The MCP16301H-450E/CH, MCP16301HT-450E/CH, MCP16301HT-E/CH, MCP16301T-E/CH, MCP16301T-E/CHY, MCP16301T-I/CHY and MCP16331T-E/CH catalog part numbers (CPN) available in 6L SOT-23 package at MTAI assembly site will qualify by similarity (QBS).



MICROCHIP

PACKAGE QUALIFICATION REPORT

Purpose Qualification of an additional mold compound G600V for the 6L SOT-23 COL package with PPF lead-frame at MTAI assembly site. The MCP16301H-450E/CH, MCP16301HT-450E/CH, MCP16301HT-E/CH, MCP16301T-E/CH, MCP16301T-E/CHY, MCP16301T-I/CHY and MCP16331T-E/CH catalog part numbers (CPN) available in 6L SOT-23 package at MTAI assembly site will qualify by similarity (QBS).

CN BC131408
QUAL ID Q13103
MP CODE GBCB4Y6AXB00
Part No. MCP663T-E/CHY
Bonding No. BDE-000371 Rev. A
CCB No. 1330.02 (Qual Date: Nov. 21, 2013) and 8080

Package

Type 6L SOT-23 COL PPF
Die thickness 8 mils
Die size 56.90 x 46.00 mils

Lead Frame

Paddle size Chip on Lead design
Material A194
Surface NiPdAu plate
Process Etch

Lead Lock

Lead Lock No
Part Number 10100604
Treatment None

Die attach material

Epoxy 8006NS
Wire Au wire
Mold Compound G600V
Plating Composition NiPdAu



MICROCHIP

PACKAGE QUALIFICATION REPORT

Manufacturing Information

Assembly Lot No.	Wafer Lot No.	Date Code
MTAI142303147	TMPE211517011.112	1336 U63
MTAI142303657	TMPE211517011.112	1336VJ7
MTAI142303664	TMPE211517011.112	1336 VJK

Result

☒ Pass ☐ Fail ☐ _____

6L SOT-23 assembled by MTAI pass reliability test per QCI-39000. This package was qualified the Moisture/Reflow Sensitivity Classification Level 1 at 260°C reflow temperature per IPC/JEDEC J-STD-020D standard.

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
Moisture/Reflow Sensitivity Classification Test (At MSL Level 1)	85°C/ 85%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH 3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243 (IPC/JEDEC J-STD-020D)	IPC/JEDEC C J-STD-020D	135	0/135	Pass	

<u>Precondition</u>	Electrical Test :+25°C and 125°C	JESD22-A113	693(0)	693		Good Devices
<u>Prior Perform</u>	System: ETS300					
<u>Reliability Tests</u> (At MSL Level 1)	Bake 150°C, 24 hrs System: CHINEE			693		
	85°C/85%RH Moisture Soak 168 hrs.			693		
	System: TABAI ESPEC Model PR-3SPH 3x Convection-Reflow 265°C max			693		
	System: Vitronics Soltec MR1243					
	Electrical Test :+25°C and 125°C System: ETS300			0/693	Pass	

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
Temp Cycle	Stress Condition: -65°C to +150°C, 500 Cycles System : TABAI ESPEC TSA-70H Inspection: External crack inspection all units under 40X Optical magnification Electrical Test: + 125°C System: ETS300	JESD22-A104	231(0)	231 0/231	Pass	Parts had been pre-conditioned at 260°C 77 units / lot
UNBIASED-HAST	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X Electrical Test: +25°C System: ETS300	JESD22-A118	231(0)	231 0/231	Pass	Parts had been pre-conditioned at 260°C 77 units / lot
HAST	Stress Condition: +130°C/85%RH, 96 hrs. Bias Volt: 6 Volts System: HAST 6000X Electrical Test: +25°C and 125°C System: ETS300	JESD22-A110	231(0)	231 0/231	Pass	Parts had been pre-conditioned at 260°C 77 units / lot
High Temperature Storage Life	Stress Condition: Bake 175°C, 504 hrs System: SHEL LAB Electrical Test : +25°C and 125°C System: ETS300	JESD22-A103	45(0)	45 0/45	Pass	45 units

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
Bond Strength Data Assembly	Wire Pull (> 2.5 grams)	M2011	30 (0) Wires	0/30	Pass	
	Bond Shear (15.00 grams)	JESD22- B116	30 (0) bonds	0/30	Pass	